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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

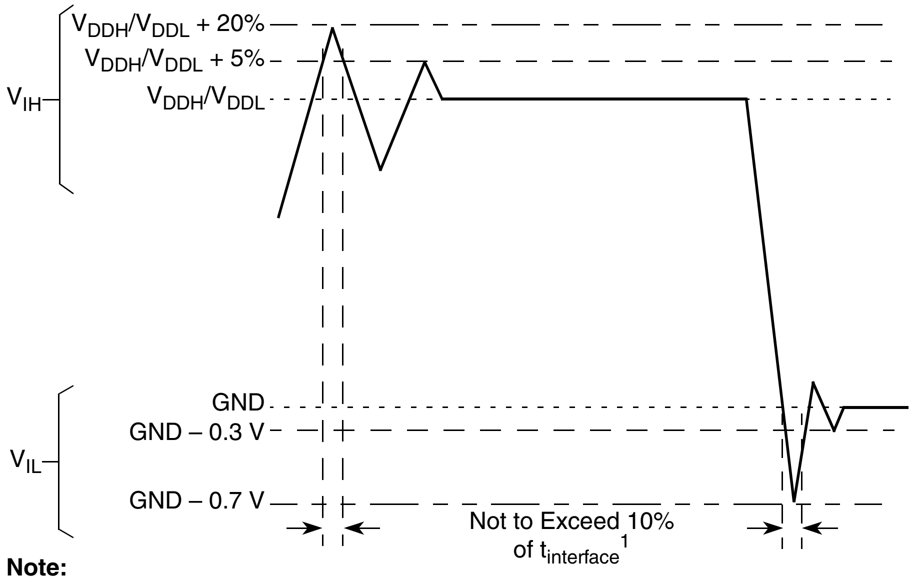
Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Active
Core Processor	MPC8xx
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	50MHz
Co-Processors/DSP	Communications; CPM
RAM Controllers	DRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10Mbps (4)
SATA	-
USB	-
Voltage - I/O	3.3V
Operating Temperature	-40°C ~ 95°C (TJ)
Security Features	-
Package / Case	357-BBGA
Supplier Device Package	357-PBGA (25x25)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mpc860enczq50d4

  - Up to 8 Kbytes of dual-port RAM
  - 16 serial DMA (SDMA) channels
  - Three parallel I/O registers with open-drain capability
- Four baud-rate generators (BRGs)
  - Independent (can be tied to any SCC or SMC)
  - Allows changes during operation
  - Autobaud support option
- Four serial communications controllers (SCCs)
  - Ethernet/IEEE 802.3® standard optional on SCC1–4, supporting full 10-Mbps operation (available only on specially programmed devices)
  - HDLC/SDLC (all channels supported at 2 Mbps)
  - HDLC bus (implements an HDLC-based local area network (LAN))
  - Asynchronous HDLC to support point-to-point protocol (PPP)
  - AppleTalk
  - Universal asynchronous receiver transmitter (UART)
  - Synchronous UART
  - Serial infrared (IrDA)
  - Binary synchronous communication (BISYNC)
  - Totally transparent (bit streams)
  - Totally transparent (frame-based with optional cyclic redundancy check (CRC))
- Two SMCs (serial management channels)
  - UART
  - Transparent
  - General circuit interface (GCI) controller
  - Can be connected to the time-division multiplexed (TDM) channels
- One SPI (serial peripheral interface)
  - Supports master and slave modes
  - Supports multimaster operation on the same bus
- One I^2C (inter-integrated circuit) port
  - Supports master and slave modes
  - Multiple-master environment support
- Time-slot assigner (TSA)
  - Allows SCCs and SMCs to run in multiplexed and/or non-multiplexed operation
  - Supports T1, CEPT, PCM highway, ISDN basic rate, ISDN primary rate, user defined
  - 1- or 8-bit resolution
  - Allows independent transmit and receive routing, frame synchronization, and clocking

Figure 1 shows the undershoot and overshoot voltages at the interface of the MPC860.



Note:
1. $t_{interface}$ refers to the clock period associated with the bus clock interface.

Figure 1. Undershoot/Overshoot Voltage for V_{DDH} and V_{DDL}

4 Thermal Characteristics

Table 3. Package Description

Package Designator	Package Code (Case No.)	Package Description
ZP	5050 (1103-01)	PBGA 357 25*25*0.9P1.27
ZQ/VR	5058 (1103D-02)	PBGA 357 25*25*1.2P1.27

Table 6. DC Electrical Specifications (continued)

Characteristic	Symbol	Min	Max	Unit
Input leakage current, V_{in} = 3.6 V (except TMS, $\overline{TRST}$, DSCK, and DSDI pins)	I_{In}	—	10	µA
Input leakage current, V_{in} = 0 V (except TMS, $\overline{TRST}$, DSCK, and DSDI pins)	I_{In}	—	10	µA
Input capacitance[2]	C_{in}	—	20	pF
Output high voltage, I_{OH} = –2.0 mA, V_{DDH} = 3.0 V (except XTAL, XFC, and open-drain pins)	V_{OH}	2.4	—	V
Output low voltage I_{OL} = 2.0 mA, CLKOUT I_{OL} = 3.2 mA [3] I_{OL} = 5.3 mA [4] I_{OL} = 7.0 mA, TXD1/PA14, TXD2/PA12 I_{OL} = 8.9 mA, $\overline{TS}$, $\overline{TA}$, $\overline{TEA}$, $\overline{BI}$, $\overline{BB}$, $\overline{HRESET}$, $\overline{SRESET}$	V_{OL}	—	0.5	V

1 V_{IL}(max) for the I^2C interface is 0.8 V rather than the 1.5 V as specified in the I^2C standard.

2 Input capacitance is periodically sampled.

3 A(0:31), TSIZ0/$\overline{REG}$, TSIZ1, D(0:31), DP(0:3)/$\overline{IRQ}$(3:6), RD/$\overline{WR}$, $\overline{BURST}$, $\overline{RSV}$/$\overline{IRQ2}$, IP_B(0:1)/IWP(0:1)/VFLS(0:1), IP_B2/IOIS16_B/AT2, IP_B3/IWP2/VF2, IP_B4/LWP0/VF0, IP_B5/LWP1/VF1, IP_B6/DSDI/AT0, IP_B7/PTR/AT3, RXD1/PA15, RXD2/PA13, L1TXDB/PA11, L1RXDB/PA10, L1TXDA/PA9, L1RXDA/PA8, TIN1/L1RCLKA/BRGO1/CLK1/PA7, BRGCLK1/$\overline{TOUT1}$/CLK2/PA6, TIN2/L1TCLKA/BRGO2/CLK3/PA5, $\overline{TOUT2}$/CLK4/PA4, TIN3/BRGO3/CLK5/PA3, BRGCLK2/L1RCLKB/$\overline{TOUT3}$/CLK6/PA2, TIN4/BRGO4/CLK7/PA1, L1TCLKB/$\overline{TOUT4}$/CLK8/PA0, $\overline{REJCT1}$/$\overline{SPISEL}$/PB31, SPICLK/PB30,SPIMOSI/PB29, BRGO4/SPIMISO/PB28, BRGO1/I2CSDA/PB27, BRGO2/I2CSCL/PB26, SMTXD1/PB25, SMRXD1/PB24, $\overline{SMSYN1}$/$\overline{SDACK1}$/PB23, $\overline{SMSYN2}$/$\overline{SDACK2}$/PB22, SMTXD2/L1CLKOB/PB21, SMRXD2/L1CLKOA/PB20, L1ST1/$\overline{RTS1}$/PB19, L1ST2/$\overline{RTS2}$/PB18, L1ST3/$\overline{L1RQB}$/PB17, L1ST4/$\overline{L1RQA}$/PB16, BRGO3/PB15, $\overline{RSTRT1}$/PB14, L1ST1/$\overline{RTS1}$/$\overline{DREQ0}$/PC15, L1ST2/$\overline{RTS2}$/$\overline{DREQ1}$/PC14, L1ST3/$\overline{L1RQB}$/PC13, L1ST4/$\overline{L1RQA}$/PC12, $\overline{CTS1}$/PC11, $\overline{TGATE1}$/$\overline{CD1}$/PC10, $\overline{CTS2}$/PC9, $\overline{TGATE2}$/$\overline{CD2}$/PC8, $\overline{SDACK2}$/L1TSYNCB/PC7, L1RSYNCB/PC6, $\overline{SDACK1}$/L1TSYNCA/PC5, L1RSYNCA/PC4, PD15, PD14, PD13, PD12, PD11, PD10, PD9, PD8, PD5, PD6, PD7, PD4, PD3, MII_MDC, MII_TX_ER, MII_EN, MII_MDIO, and MII_TXD[0:3]

4 $\overline{BDIP}$/$\overline{GPL\_B}$(5), $\overline{BR}$, $\overline{BG}$, FRZ/$\overline{IRQ6}$, $\overline{CS}$(0:5), $\overline{CS}$(6)/$\overline{CE}$(1)_B, $\overline{CS}$(7)/$\overline{CE}$(2)_B, $\overline{WE0}$/$\overline{BS}$_B0/$\overline{IORD}$, $\overline{WE1}$/$\overline{BS}$_B1/$\overline{IOWR}$, $\overline{WE2}$/$\overline{BS}$_B2/$\overline{PCOE}$, $\overline{WE3}$/$\overline{BS}$_B3/$\overline{PCWE}$, $\overline{BS}$_A(0:3), $\overline{GPL\_A0}$/$\overline{GPL\_B0}$, $\overline{OE}$/$\overline{GPL\_A1}$/$\overline{GPL\_B1}$, $\overline{GPL\_A}$(2:3)/$\overline{GPL\_B}$(2:3)/$\overline{CS}$(2:3), UPWAITA/$\overline{GPL\_A4}$, UPWAITB/$\overline{GPL\_B4}$, $\overline{GPL\_A5}$, ALE_A, $\overline{CE1}$_A, $\overline{CE2}$_A, ALE_B/DSCK/AT1, OP(0:1), OP2/MODCK1/$\overline{STS}$, OP3/MODCK2/DSDO, and BADDR(28:30)

7 Thermal Calculation and Measurement

For the following discussions, $P_D = (V_{DD} \times I_{DD}) + PI/O$, where PI/O is the power dissipation of the I/O drivers.

7.1 Estimation with Junction-to-Ambient Thermal Resistance

An estimation of the chip junction temperature, T_J, in ºC can be obtained from the equation:

$$T_J = T_A + (R_{\theta JA} \times P_D)$$

where:

T_A = ambient temperature (ºC)

$R_{\theta JA}$ = package junction-to-ambient thermal resistance (ºC/W)

P_D = power dissipation in package

The junction-to-ambient thermal resistance is an industry standard value which provides a quick and easy estimation of thermal performance. However, the answer is only an estimate; test cases have demonstrated that errors of a factor of two (in the quantity $T_J - T_A$) are possible.

7.2 Estimation with Junction-to-Case Thermal Resistance

Historically, the thermal resistance has frequently been expressed as the sum of a junction-to-case thermal resistance and a case-to-ambient thermal resistance:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$$

where:

$R_{\theta JA}$ = junction-to-ambient thermal resistance (ºC/W)

$R_{\theta JC}$ = junction-to-case thermal resistance (ºC/W)

$R_{\theta CA}$ = case-to-ambient thermal resistance (ºC/W)

$R_{\theta JC}$ is device related and cannot be influenced by the user. The user adjusts the thermal environment to affect the case-to-ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the airflow around the device, add a heat sink, change the mounting arrangement on the printed-circuit board, or change the thermal dissipation on the printed-circuit board surrounding the device. This thermal model is most useful for ceramic packages with heat sinks where some 90% of the heat flows through the case and the heat sink to the ambient environment. For most packages, a better model is required.

7.3 Estimation with Junction-to-Board Thermal Resistance

A simple package thermal model which has demonstrated reasonable accuracy (about 20%) is a two-resistor model consisting of a junction-to-board and a junction-to-case thermal resistance. The junction-to-case thermal resistance covers the situation where a heat sink is used or where a substantial amount of heat is dissipated from the top of the package. The junction-to-board thermal resistance describes the thermal performance when most of the heat is conducted to the printed-circuit board. It has been observed that the thermal performance of most plastic packages, especially PBGA packages, is strongly dependent on the board temperature; see Figure 2.

Figure 5 provides the timing for the synchronous output signals.

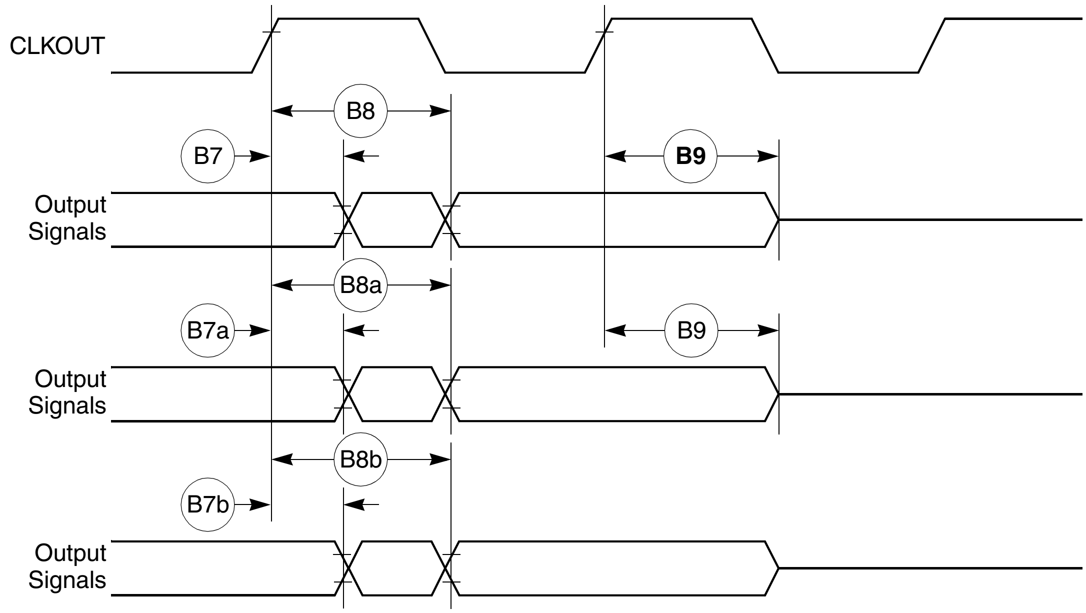


Figure 5. Synchronous Output Signals Timing

Figure 6 provides the timing for the synchronous active pull-up and open-drain output signals.

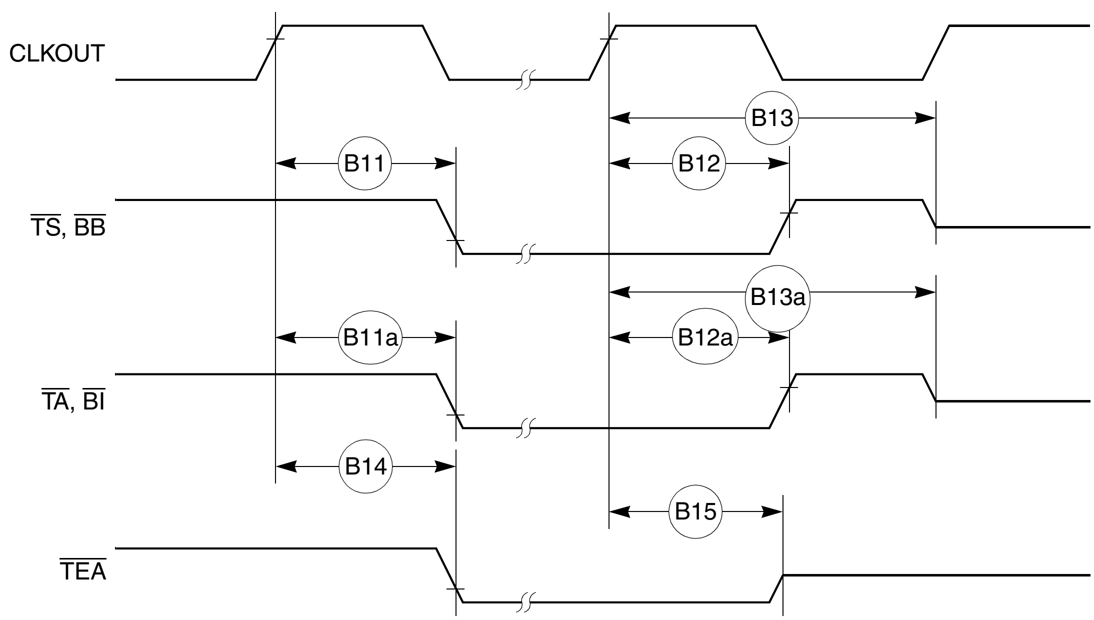


Figure 6. Synchronous Active Pull-Up Resistor and Open-Drain Outputs Signals Timing

Figure 20 provides the timing for the synchronous external master access controlled by the GPCM.

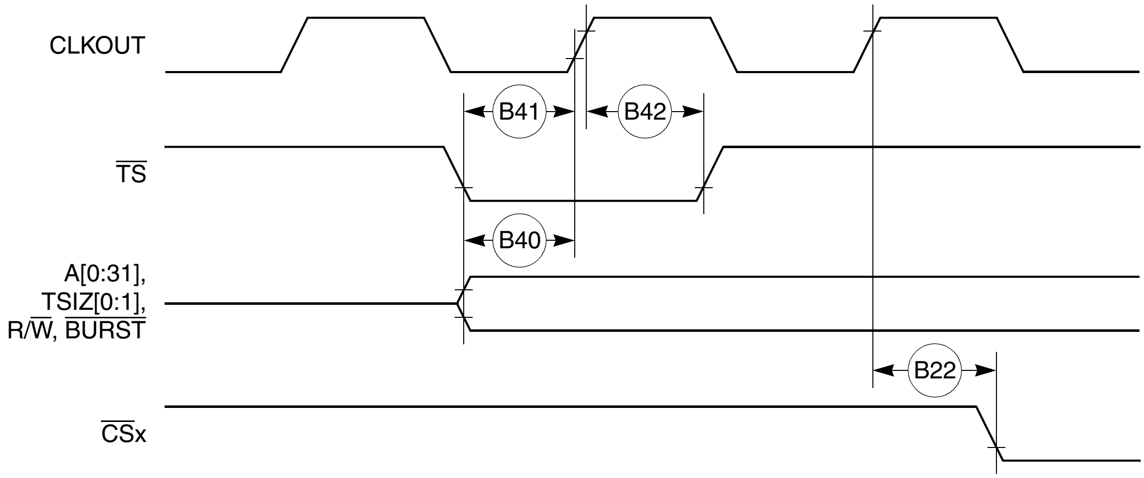


Figure 20. Synchronous External Master Access Timing (GPCM Handled ACS = 00)

Figure 21 provides the timing for the asynchronous external master memory access controlled by the GPCM.

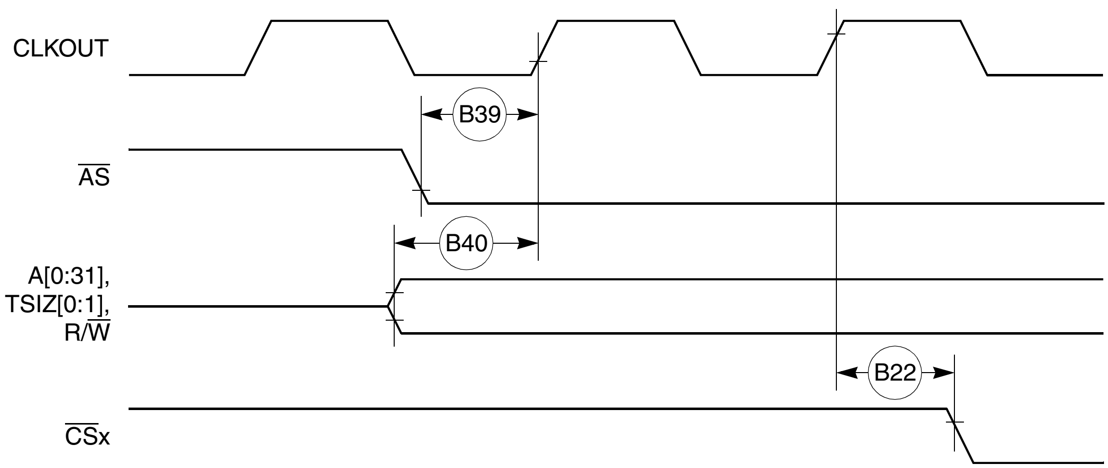


Figure 21. Asynchronous External Master Memory Access Timing (GPCM Controlled—ACS = 00)

Figure 22 provides the timing for the asynchronous external master control signals negation.

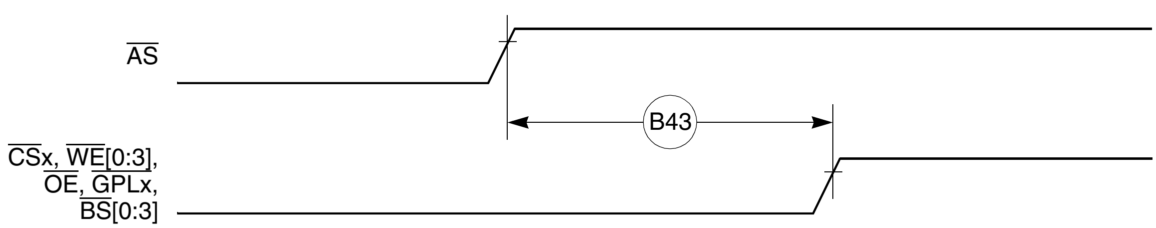


Figure 22. Asynchronous External Master—Control Signals Negation Timing

Figure 26 provides the PCMCIA access cycle timing for the external bus write.

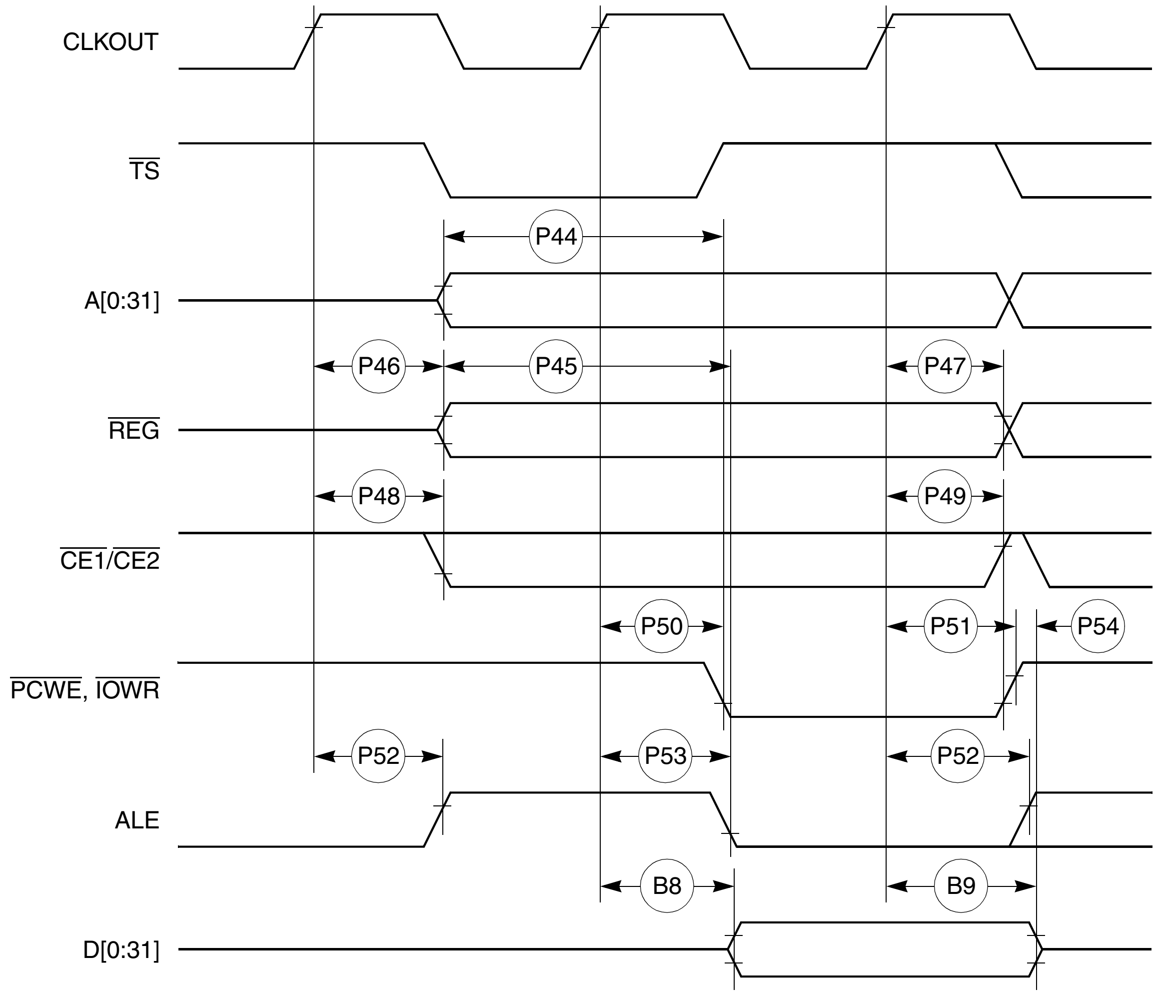


Figure 26. PCMCIA Access Cycle Timing External Bus Write

Figure 27 provides the PCMCIA $\overline{\text{WAIT}}$ signal detection timing.

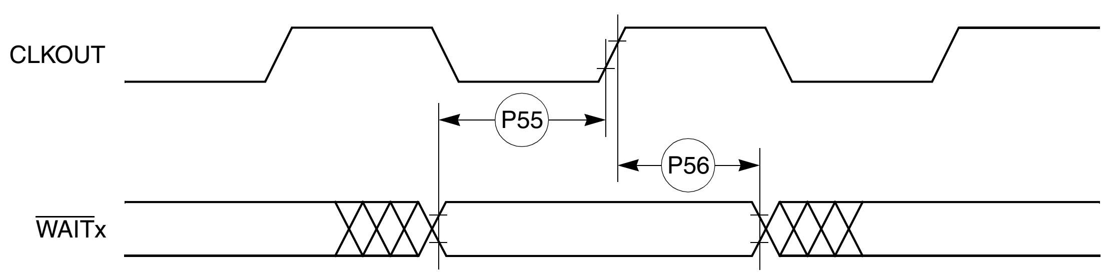


Figure 27. PCMCIA $\overline{\text{WAIT}}$ Signal Detection Timing

Figure 32 shows the reset timing for the data bus configuration.

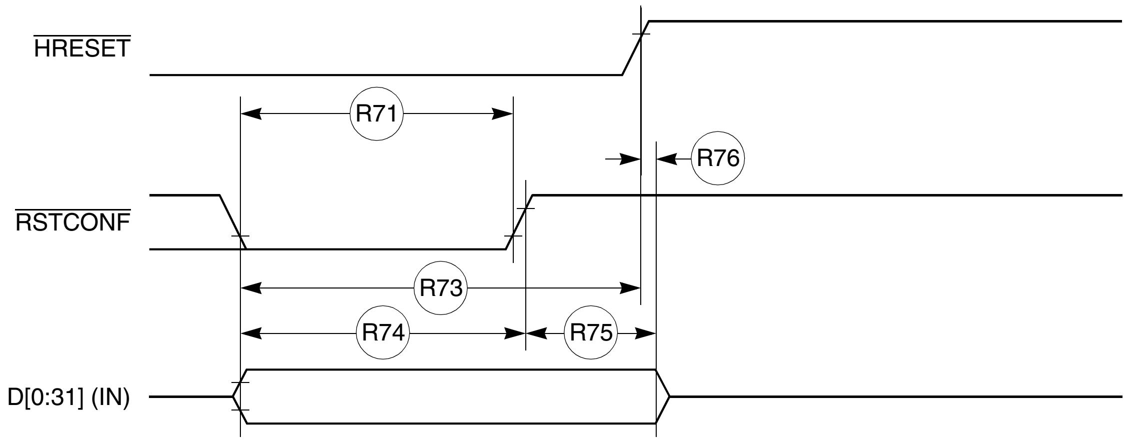


Figure 32. Reset Timing—Configuration from Data Bus

Figure 33 provides the reset timing for the data bus weak drive during configuration.

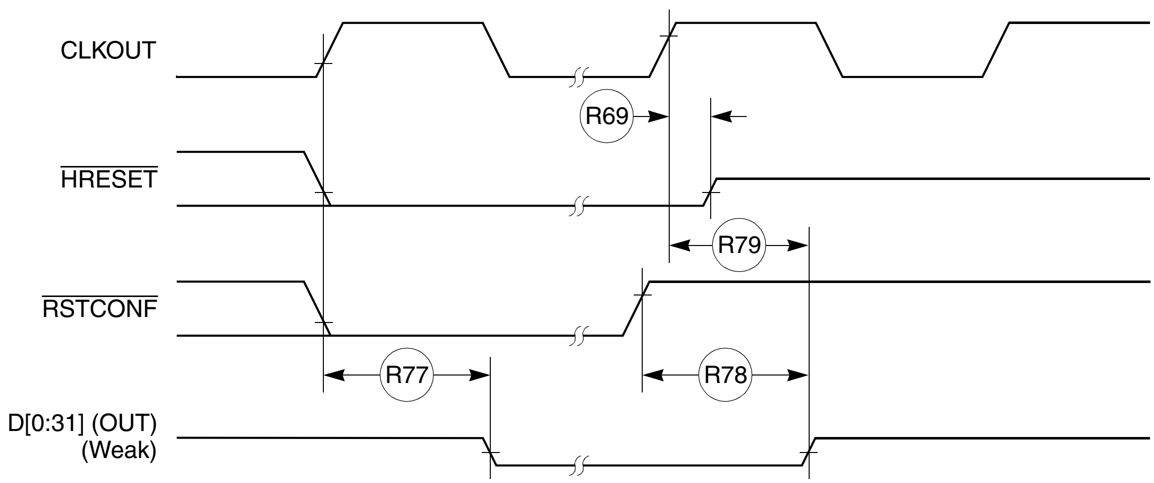


Figure 33. Reset Timing—Data Bus Weak Drive During Configuration

Figure 34 provides the reset timing for the debug port configuration.

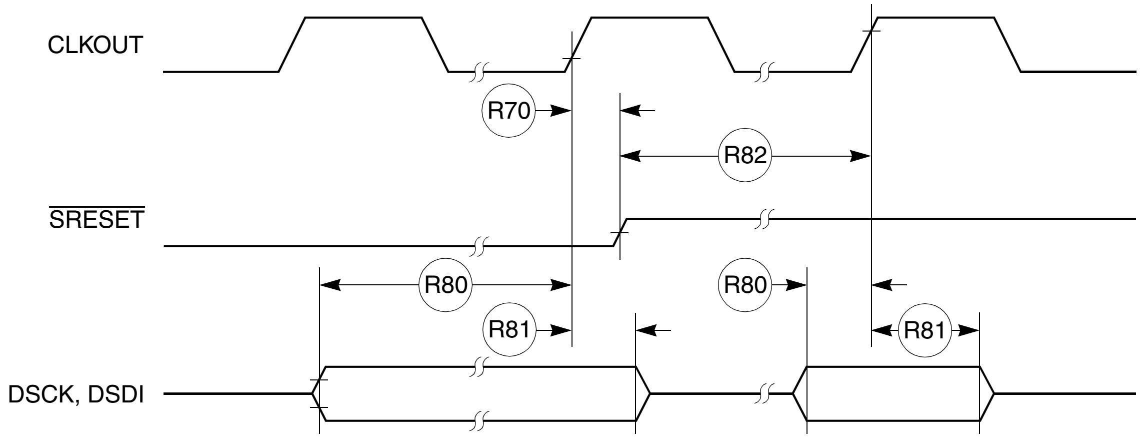


Figure 34. Reset Timing—Debug Port Configuration

10 IEEE 1149.1 Electrical Specifications

Table 13 provides the JTAG timings for the MPC860 shown in Figure 35 through Figure 38.

Table 13. JTAG Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
J82	TCK cycle time	100.00	—	ns
J83	TCK clock pulse width measured at 1.5 V	40.00	—	ns
J84	TCK rise and fall times	0.00	10.00	ns
J85	TMS, TDI data setup time	5.00	—	ns
J86	TMS, TDI data hold time	25.00	—	ns
J87	TCK low to TDO data valid	—	27.00	ns
J88	TCK low to TDO data invalid	0.00	—	ns
J89	TCK low to TDO high impedance	—	20.00	ns
J90	$\overline{\text{TRST}}$ assert time	100.00	—	ns
J91	$\overline{\text{TRST}}$ setup time to TCK low	40.00	—	ns
J92	TCK falling edge to output valid	—	50.00	ns
J93	TCK falling edge to output valid out of high impedance	—	50.00	ns
J94	TCK falling edge to output high impedance	—	50.00	ns
J95	Boundary scan input valid to TCK rising edge	50.00	—	ns
J96	TCK rising edge to boundary scan input invalid	50.00	—	ns

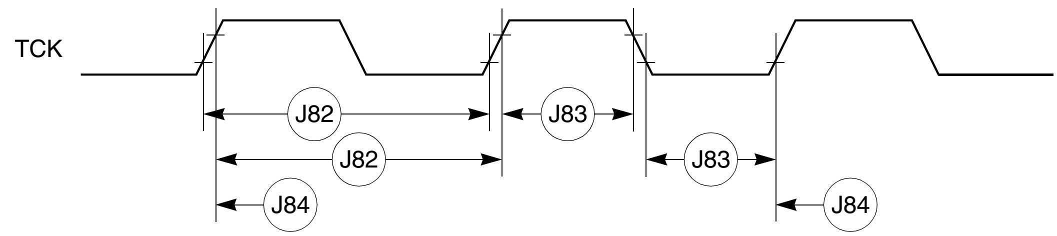


Figure 35. JTAG Test Clock Input Timing

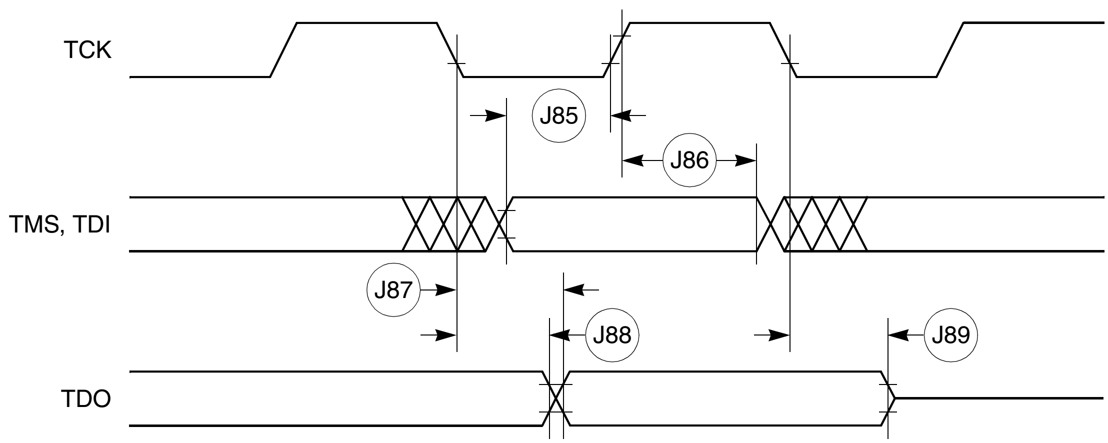


Figure 36. JTAG Test Access Port Timing Diagram

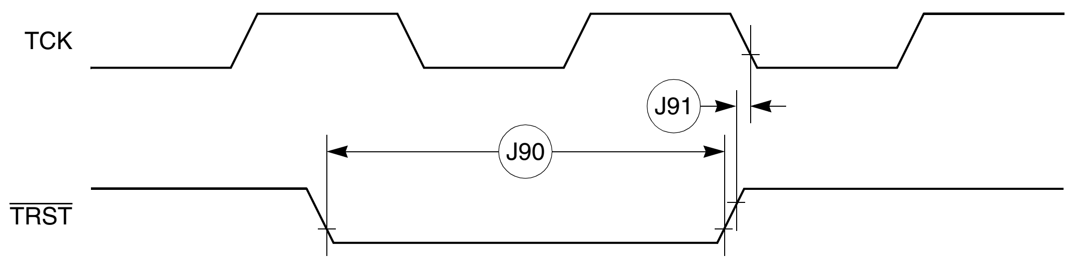


Figure 37. JTAG TRST Timing Diagram

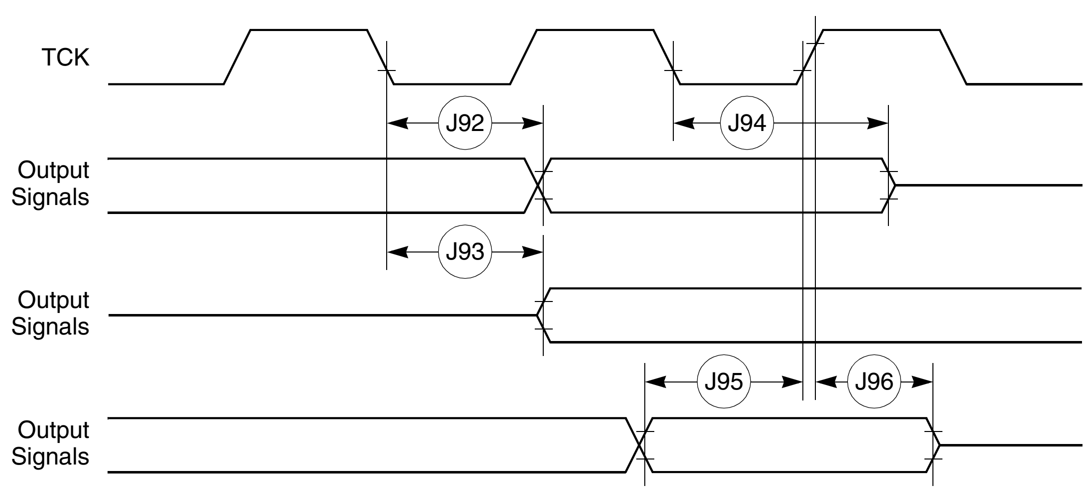


Figure 38. Boundary Scan (JTAG) Timing Diagram

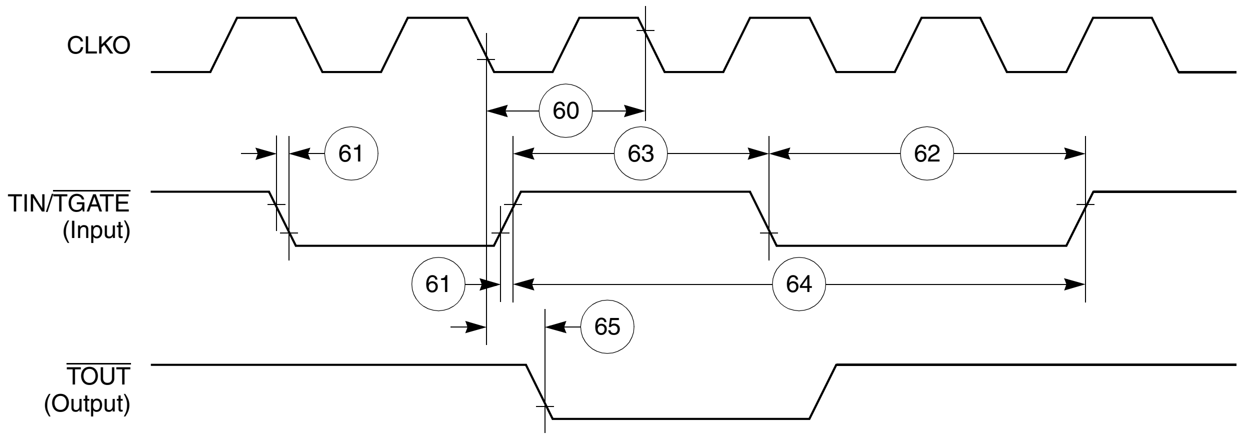


Figure 50. CPM General-Purpose Timers Timing Diagram

11.6 Serial Interface AC Electrical Specifications

Table 19 provides the serial interface timings as shown in Figure 51 through Figure 55.

Table 19. SI Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
70	L1RCLK, L1TCLK frequency (DSC = 0)[1, 2]	—	SYNCCLK/2.5	MHz
71	L1RCLK, L1TCLK width low (DSC = 0)[2]	P + 10	—	ns
71a	L1RCLK, L1TCLK width high (DSC = 0)[3]	P + 10	—	ns
72	L1TXD, L1ST(1–4), $\overline{\text{L1RQ}}$, L1CLKO rise/fall time	—	15.00	ns
73	L1RSYNC, L1TSYNC valid to L1CLK edge (SYNC setup time)	20.00	—	ns
74	L1CLK edge to L1RSYNC, L1TSYNC, invalid (SYNC hold time)	35.00	—	ns
75	L1RSYNC, L1TSYNC rise/fall time	—	15.00	ns
76	L1RXD valid to L1CLK edge (L1RXD setup time)	17.00	—	ns
77	L1CLK edge to L1RXD invalid (L1RXD hold time)	13.00	—	ns
78	L1CLK edge to L1ST(1–4) valid [4]	10.00	45.00	ns
78A	L1SYNC valid to L1ST(1–4) valid	10.00	45.00	ns
79	L1CLK edge to L1ST(1–4) invalid	10.00	45.00	ns
80	L1CLK edge to L1TXD valid	10.00	55.00	ns
80A	L1TSYNC valid to L1TXD valid [4]	10.00	55.00	ns
81	L1CLK edge to L1TXD high impedance	0.00	42.00	ns
82	L1RCLK, L1TCLK frequency (DSC =1)	—	16.00 or SYNCCLK/2	MHz
83	L1RCLK, L1TCLK width low (DSC = 1)	P + 10	—	ns
83a	L1RCLK, L1TCLK width high (DSC = 1)[3]	P + 10	—	ns

Table 19. SI Timing (continued)

Num	Characteristic	All Frequencies		Unit
		Min	Max	
84	L1CLK edge to L1CLKO valid (DSC = 1)	—	30.00	ns
85	$\overline{\text{L1RQ}}$ valid before falling edge of L1TSYNC[4]	1.00	—	L1TCLK
86	L1GR setup time[2]	42.00	—	ns
87	L1GR hold time	42.00	—	ns
88	L1CLK edge to L1SYNC valid (FSD = 00) CNT = 0000, BYT = 0, DSC = 0)	—	0.00	ns

1 The ratio SYNCCLK/L1RCLK must be greater than 2.5/1.
2 These specs are valid for IDL mode only.
3 Where P = 1/CLKOUT. Thus, for a 25-MHz CLKO1 rate, P = 40 ns.
4 These strobes and TxD on the first bit of the frame become valid after L1CLK edge or L1SYNC, whichever comes later.

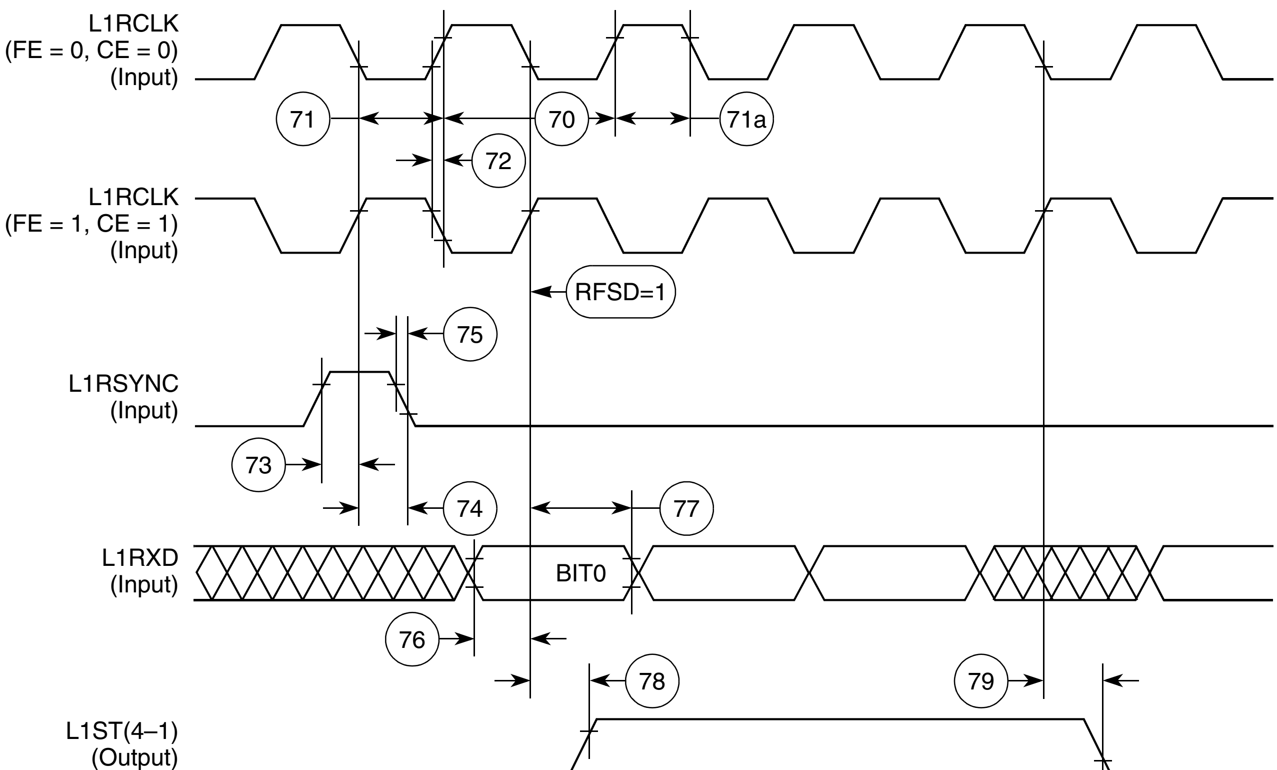


Figure 51. SI Receive Timing Diagram with Normal Clocking (DSC = 0)

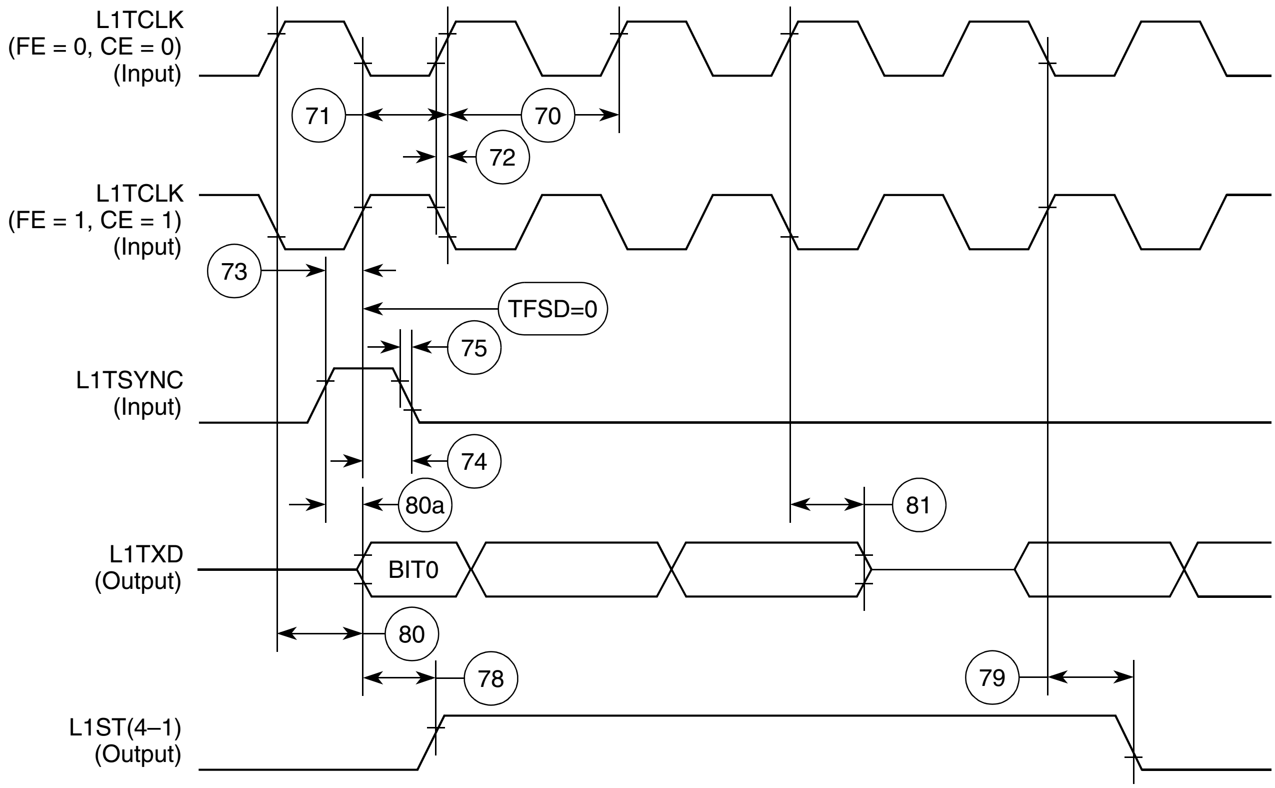


Figure 53. SI Transmit Timing Diagram (DSC = 0)

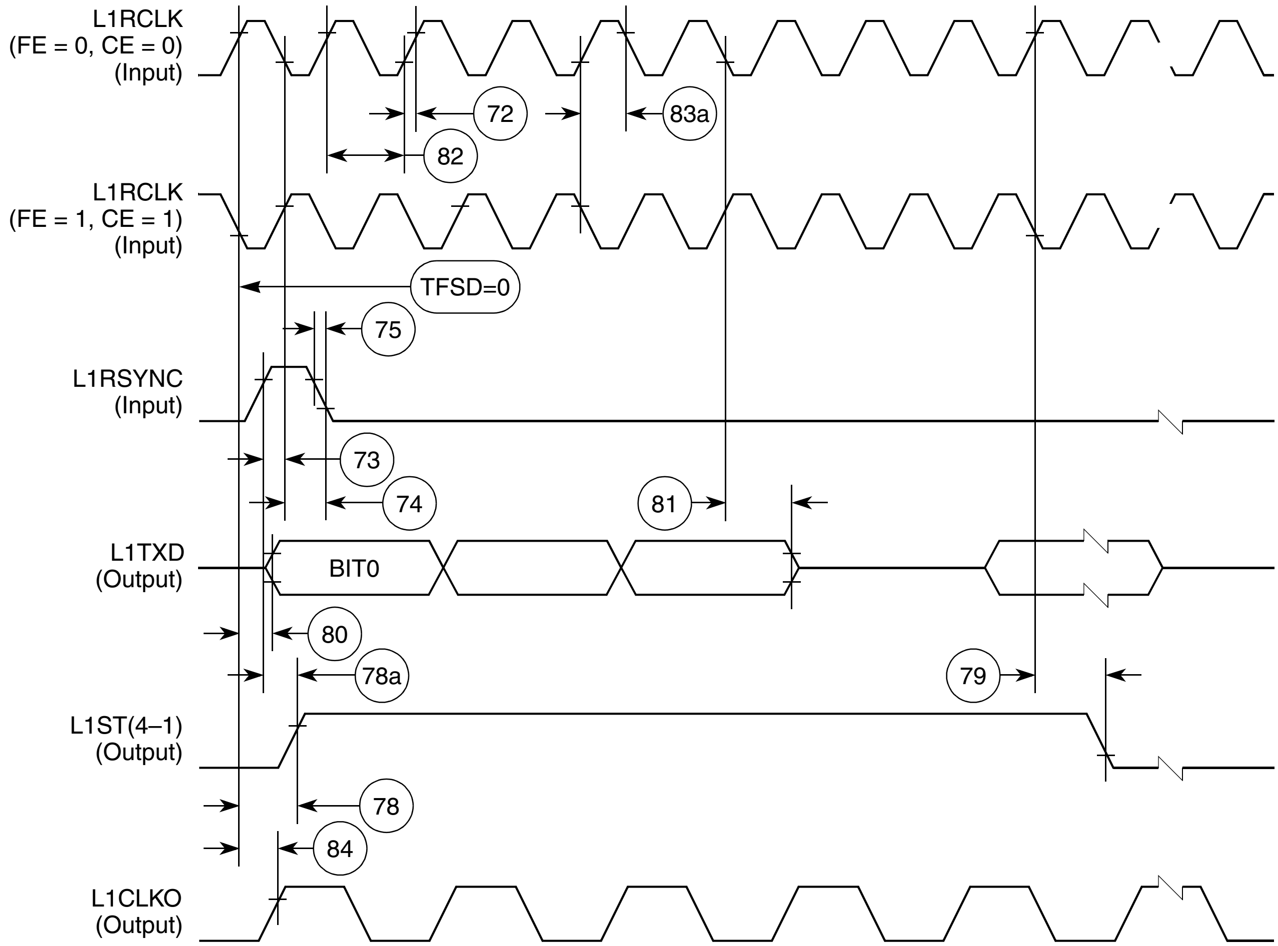


Figure 54. SI Transmit Timing with Double Speed Clocking (DSC = 1)

11.10 SPI Master AC Electrical Specifications

Table 24 provides the SPI master timings as shown in Figure 65 and Figure 66.

Table 24. SPI Master Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
160	MASTER cycle time	4	1024	t_{cyc}
161	MASTER clock (SCK) high or low time	2	512	t_{cyc}
162	MASTER data setup time (inputs)	50	—	ns
163	Master data hold time (inputs)	0	—	ns
164	Master data valid (after SCK edge)	—	20	ns
165	Master data hold time (outputs)	0	—	ns
166	Rise time output	—	15	ns
167	Fall time output	—	15	ns

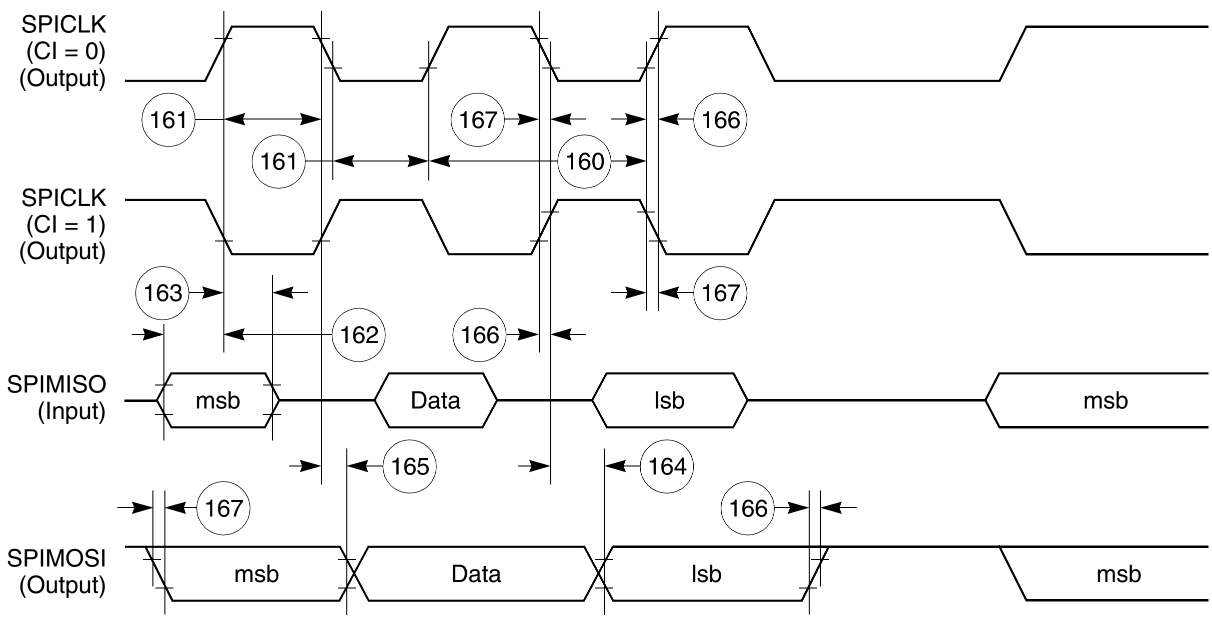


Figure 65. SPI Master (CP = 0) Timing Diagram

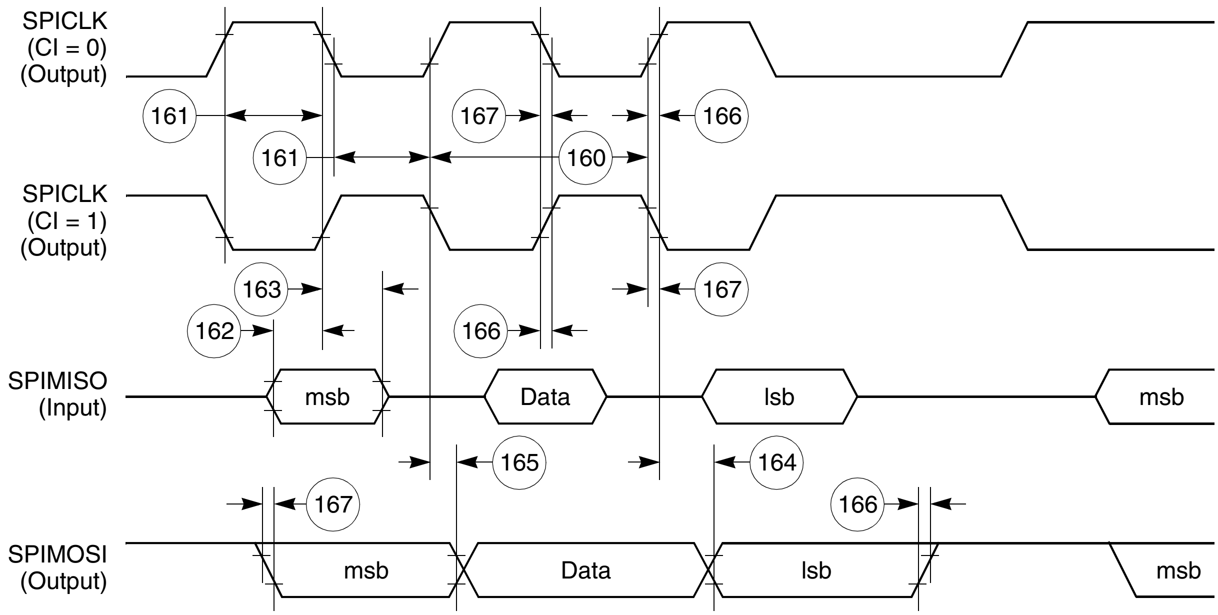


Figure 66. SPI Master (CP = 1) Timing Diagram

11.11 SPI Slave AC Electrical Specifications

Table 25 provides the SPI slave timings as shown in Figure 67 and Figure 68.

Table 25. SPI Slave Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
170	Slave cycle time	2	—	t_{cyc}
171	Slave enable lead time	15	—	ns
172	Slave enable lag time	15	—	ns
173	Slave clock (SPICLK) high or low time	1	—	t_{cyc}
174	Slave sequential transfer delay (does not require deselect)	1	—	t_{cyc}
175	Slave data setup time (inputs)	20	—	ns
176	Slave data hold time (inputs)	20	—	ns
177	Slave access time	—	50	ns

14.2 Pin Assignments

Figure 76 shows the top view pinout of the PBGA package. For additional information, see the *MPC860 PowerQUICC User's Manual*, or the *MPC855T User's Manual*.

NOTE: This is the top view of the device.

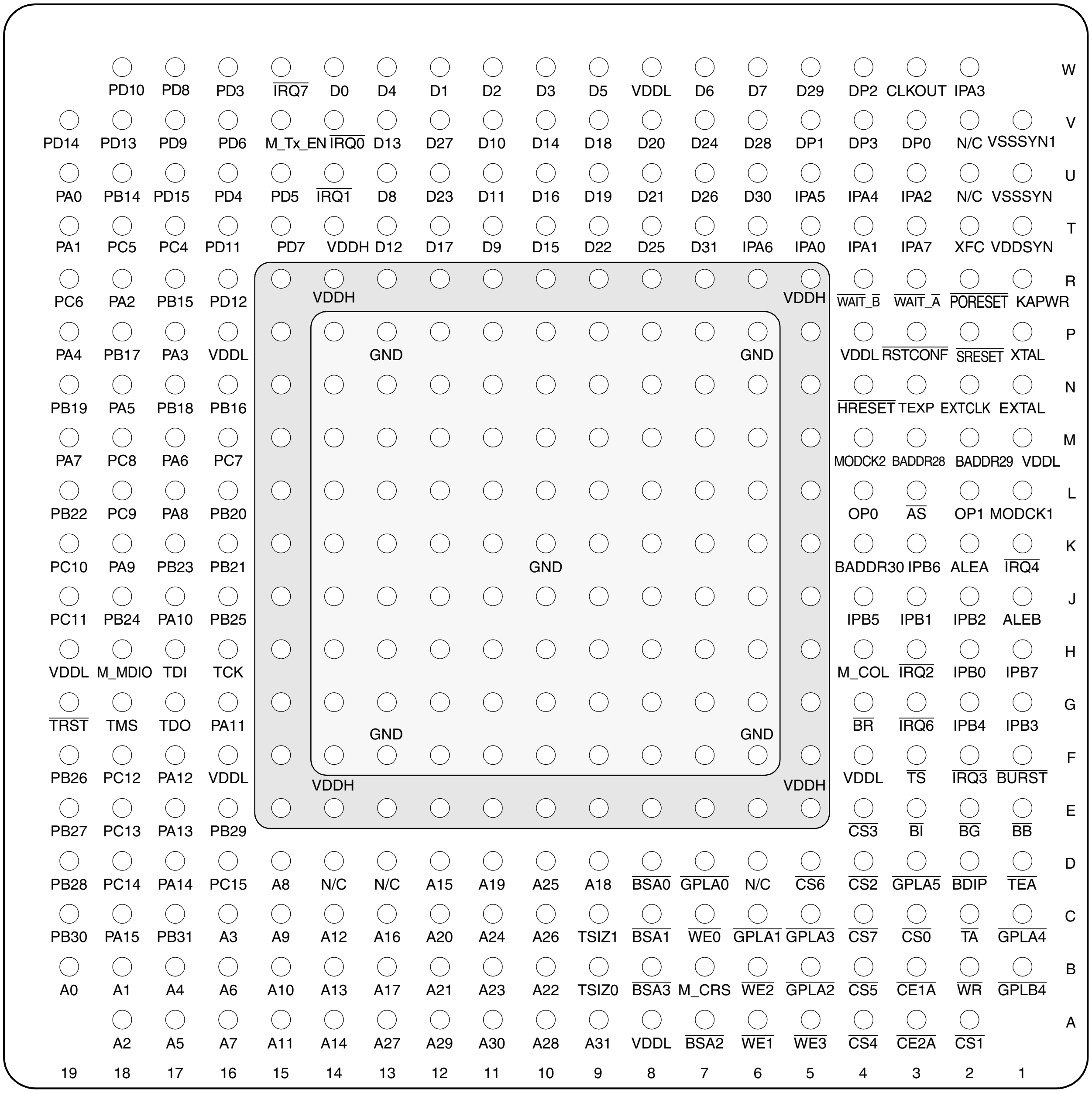
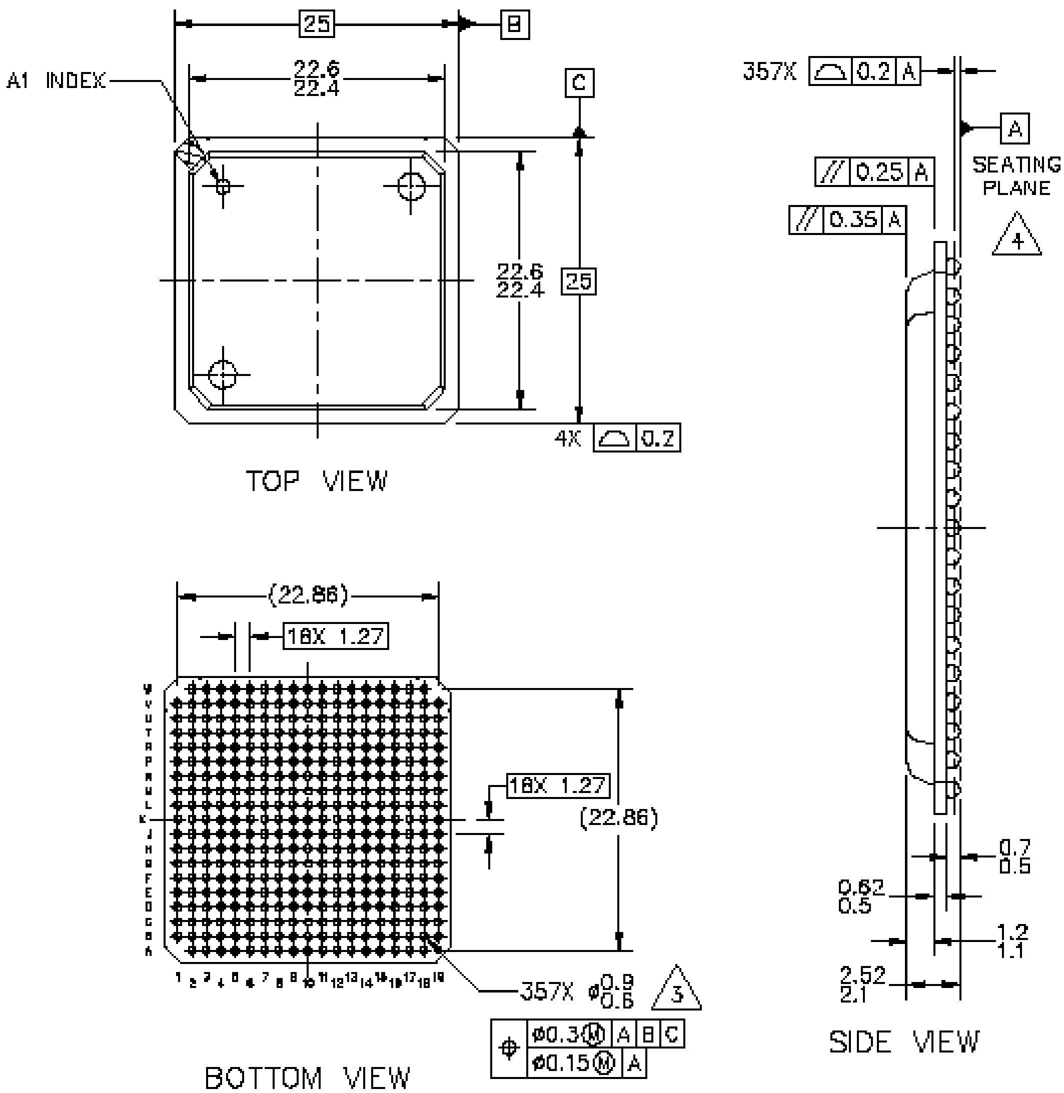


Figure 76. Pinout of the PBGA Package

Figure 78 shows the mechanical dimensions of the ZQ PBGA package.



NOTE

1. All Dimensions in millimeters.
2. Dimensions and tolerance per ASME Y14.5M, 1994.
3. Maximum Solder Ball Diameter measured parallel to Datum A.
4. Datum A, the seating plane, is defined by the spherical crowns of the solder balls.

Figure 78. Mechanical Dimensions and Bottom Surface Nomenclature of the ZQ PBGA Package

15 Document Revision History

Table 35 lists significant changes between revisions of this hardware specification.

Table 35. Document Revision History

Revision	Date	Changes
10	09/2015	In Table 34, moved MPC855TCVR50D4 and MPC855TCVR66D4 under the extended temperature (–40° to 95°C) and removed MC860ENCVR50D4R2 from the normal temperature Tape and Reel.
9	10/2011	Updated orderable part numbers in Table 34, “MPC860 Family Package/Frequency Availability.”
8	08/2007	• Updated template. • On page 1, added a second paragraph. • After Table 2, inserted a new figure showing the undershoot/overshoot voltage (Figure 1) and renumbered the rest of the figures. • In Figure 3, changed all reference voltage measurement points from 0.2 and 0.8 V to 50% level. • In Table 16, changed num 46 description to read, “$\overline{TA}$ assertion to rising edge ...” • In Figure 46, changed $\overline{TA}$ to reflect the rising edge of the clock.
7.0	9/2004	• Added a tablefootnote to Table 6 DC Electrical Specifications about meeting the VIL Max of the I2C Standard • Replaced the thermal characteristics in Table 4 by the ZQ package • Add the new parts to the Ordering and Availablity Chart in Table 34 • Added the mechanical spec of the ZQ package in Figure 78 • Removed all of the old revisions from Table 5
6.3	9/2003	• Added Section 11.2 on the Port C interrupt pins • Nontechnical reformatting
6.2	8/2003	• Changed B28a through B28d and B29d to show that TRLX can be 0 or 1 • Changed reference documentation to reflect the Rev 2 MPC860 PowerQUICC Family Users Manual • Nontechnical reformatting
6.1	11/2002	• Corrected UTOPIA RXenb* and TXenb* timing values • Changed incorrect usage of Vcc to Vdd • Corrected dual port RAM to 8 Kbytes
6	10/2002	• Added the MPC855T. Corrected Figure 26 on page -36.
5.1	11/2001	• Revised template format, removed references to MAC functionality, changed Table 7 B23 max value @ 66 MHz from 2ns to 8ns, added this revision history table

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